

<b>Notice of References Cited</b>	Application/Control No. 10/615,799	Applicant(s)/Patent Under Reexamination FURUMIYA ET AL.	
	Examiner MUHAMMAD N. EDUN	Art Unit 2655	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,667,949	12-2003	Stek et al.	369/275.3
X	B	US-5,295,131	03-1994	Ishibashi et al.	369/275.3
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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